

Resource Summary Report

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Hitachi: S3000N Scanning Electron Microscope

RRID:SCR_020029

Type: Tool

Proper Citation

Hitachi: S3000N Scanning Electron Microscope (RRID:SCR_020029)

Resource Information

URL: <https://uwaterloo.ca/giga-to-nanoelectronics-centre/hitachi-s-3000n-scanning-electron-microscope>

Proper Citation: Hitachi: S3000N Scanning Electron Microscope (RRID:SCR_020029)

Description: Hitachi S-3000N scanning electron microscope (SEM) is a PC controlled variable pressure SEM with the ability to switch between the high vacuum and variable pressure modes. It has a high density frame memory of 1280x960 pixels and an advanced image capture and archiving system. Four quadrant solid state backscatter allows imaging in the compositional, 3D and topographic modes by manipulating from each segment of the detector.

Resource Type: instrument resource

Keywords: Hitachi, Scanning Electron Microscope, Instrument Equipment, USEDit

Availability: Commercially available

Resource Name: Hitachi: S3000N Scanning Electron Microscope

Resource ID: SCR_020029

Alternate IDs: Model_Number_S3000N

Record Creation Time: 20220129T080348+0000

Record Last Update: 20260801T190642+0000

Ratings and Alerts

No rating or validation information has been found for Hitachi: S3000N Scanning Electron Microscope.

No alerts have been found for Hitachi: S3000N Scanning Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.